POWER THE FUTURE



# INNEHB650A5 Evaluation Board Manual 650V GaN HEMT INN650TA030AH

Open Loop Half Bridge EVB





## CAUTION

Please carefully read the following content since it contains critical information about safety and the possible hazard it may cause by incorrect use.

## 🛕 ELECTRICAL SHOCK HAZARD

There is a dangerous voltage on the demo board, and exposure to high voltage may lead to safety problems such as injury or death.

Proper operating and safety procedures must be adhered to and used only for laboratory evaluation demonstrations and not directly to end-user equipment.

## 🛕 HOT SURFACE

The surface of PCB can be hot and could cause burns. DO NOT TOUCH THE PCB WHILE OPERATING!!

## 🚵 REMINDER

This product contains parts that are susceptible to electrostatic discharge (ESD). When using this product, be sure to follow antistatic procedures.

## List of Content

1. Overview
1.1. Introduction1
1.2. Test equipment requirement1
2. Parameters
3. Block diagram
4. PCBA overview and schematic4
4.1. PCBA overview4
4.2. Schematic
5. Testing guide6
5.1. Test point location6
5.2. Test setup7
5.2.1. Buck mode7
5.2.2. Boost mode7
5.2.3. Double pulse test mode8
5.3. Power up and down sequence9
5.3.1. Power-up sequence (Buck mode)9
5.3.2. Power-up sequence (Boost mode)9
5.3.3. Power-up sequence (Double pulse test mode)10
5.3.4. Power-down sequence11
6. Evaluation results12
6.1. Double pulse test waveform12
6.2. Boost mode waveform13
6.2.1. Switching waveforms (Rgon=10Ω, Rgoff=2.2Ω)13
6.2.2. Efficiency results15
6.2.3. Thermal performance15
Appendix17
Appendix A: INNEHB650A5 PCB layout17
Appendix B: INNEHB650A5 BOM19
Revision history

### 1. Overview

#### 1.1. Introduction

INNEHB650A5 is a half-bridge evaluation board equipped with isolator and INNO own gate driver INS1001 to evaluate the performance of 650V GaN HEMT with INN650TA030AH. This board can simplify the test process, it can easily achieve Buck/ Boost converter and double pulse test system with dual PWM input. The board includes all the necessary information you need, and the layout has been optimized to achieve the best performance. Test points are also included for the waveform measurement.

### 1.2. Test equipment requirement

To evaluate the performance properly, you need to prepare the following test equipment:

- 1) High speed digital oscilloscope (>500MHz Bandwidth)
- 2) Low voltage DC power supply
- 3) PWM generator
- 4) Digital Multimeter
- 5) DC load (E-load or Power Resistor)

## 2. Parameters

#### Table 1 Electrical Characteristic (Ta=25°C)

Symbol	Parameters Min Nom		Nom	Max	Units
VDD	VDD supply voltage	4.5	4.5 5		V
Vin/Vout	Input Voltage			450	V
Pout	Output Power			4000(1)	W
Vpwm	Input Logic 'High'	3.5		5	V
	Input Logic 'Low'	0		1.5	V

(1) Maximum output power depends on device temperature – actual maximum output power with be subject to switching frequency, bus voltage, load current and thermal cooling.

## 3. Block diagram



Figure 1 INNEHB650A5 Block Diagram

## 4. PCBA overview and schematic

#### 4.1. PCBA overview



Figure 2 Top view of INNEHB650A5

### 4.2. Schematic





## 5. Testing guide

### 5.1.Test point location



Figure 4 Measurement points of INNEHB650A5

#### 5.2. Test setup

#### 5.2.1. Buck mode



#### Figure 5 Buck mode

#### 5.2.2. Boost mode



#### Figure 6 Boost mode

#### 5.2.3. Double pulse test mode



Figure 7 Double pulse test mode

#### 5.3. Power up and down sequence

#### 5.3.1. Power-up sequence (Buck mode)

- 1. Check every power supply is **off.**
- 2. Connect the DC voltage source to VIN terminal **VBULK** and common ground terminal **powerGND**, as shown in Figure 5 (Pay attention to the polarity).
- 3. Connect the electronic load to pin **HB**.
- Connect the auxiliary source to the VDD terminal GAN\_DRV (Pay attention to the polarity).
- 5. Connect the signal generator to pin **GDH**, **GDL**. Note set enough dead time to make sure two GaN HEMT will not short. Recommend set as 200ns as initial.
- 6. Turn on the auxiliary power supply.
- 7. Open the signal generator and enter the PWM signal with the required duty ratio and frequency.
- 8. Make sure the initial input supply voltage is 0 V, turn on the power and slowly increase the voltage to the desired value (**do not exceed the absolute maximum voltage**). Probe switchnode and view the switching operation.
- 9. Once operational, according to the heating state of the device slowly increase the load current, do not exceed the maximum temperature required by the device specification.

#### 5.3.2. Power-up sequence (Boost mode)

- 1. Check every power supply is off
- 2. Connect the DC voltage source to pin **HB**, as shown in Figure 6 (Pay attention to the polarity).
- 3. Connect the positive pole of the electronic load to pin **VBULK** and the negative pole to pin **powerGND**.
- Connect the auxiliary source to the VDD terminal GAN\_DRV (Pay attention to the polarity).

- 5. Connect the signal generator to pin **GDH**, **GDL**. Note set enough dead time to make sure two GaN HEMT will not short. Recommend set as 200ns as initial.
- 6. Turn on the auxiliary power supply.
- 7. Open the signal generator and enter the PWM signal with the required duty ratio and frequency.
- Make sure the initial input supply voltage is 0 V, turn on the power and slowly increase the voltage to the desired value (do not exceed the absolute maximum voltage). Probe switchnode and view the switching operation.
- Once operational, according to the heating state of the device slowly increase the load current, do not exceed the maximum temperature required by the device specification.

#### 5.3.3. Power-up sequence (Double pulse test mode)

- 1. Check every power supply is off.
- 2. Connect the DC voltage source to VIN terminal **VBULK** and common ground terminal **powerGND**, as shown in Figure 7 (Pay attention to the polarity).
- 3. Connect the inductor to pin Vbulk and HB.
- Connect the auxiliary source to the VDD terminal GAN\_DRV (Pay attention to the polarity).
- 5. Connect the signal generator to pin **GDH**, **GDL**. Set signal generator as single pulse waveform mode, set pulse number as 2 pulse. Signal in GDH and GDL must be complementary. Note set enough dead time to make sure two GaN HEMT will not short. Recommend set as 200ns as initial.
- 6. Turn on the auxiliary power supply.
- Set main input Voltage to 400V. Then open the signal generator and enter the PWM signal to run double pulse test.



#### 5.3.4. Power-down sequence

- 1. Turn off the E-load first
- 2. Turn off the DC voltage source
- 3. Turn off the PWM generator
- 4. Turn off the auxiliary power supply

## 6. Evaluation results

### 6.1. Double pulse test waveform



#### 6.2. Boost mode waveform

#### 6.2.1.Switching waveforms (Rgon=10 $\Omega$ , Rgoff=2.2 $\Omega$ )



## EVB016-INNEHB650A5

波形视图

IL

Vgs

Vds

编辑 辅助功能

Vds

Vgs

⊾IL

波形视图

C3

650V GaN HEMT Open Loop Half-Bridge EVB

#### **Innoscience** 文件 编辑 辅助功能 帮助 添加新... ŏ 光标 Callo 測量 搜索 结果表 绘图 P, t: 69.086416 µs t: 68.940213 µs Δt: 146.204 ns 1/Δt: 6.84 MHz Maximum u': 6.324 V Maximum Tf\_gs: 9.99ns Maximum u': 2.423 / Tr sw:147.3ns Rise Time Fall Time u.: 149.2 r Rise Time D Fall Time 🧹 5.12 V 100 V/div 5 A/div 1 MΩ 1 MΩ 20 µs/div 200 µs SR: 1.25 GS/s 800 ps/pt 1 数学 参考 总线 手动・ 分 取样: 12 bits 04 May 202 Test conditions 添加新. **B** C4 光标 Call Vin=200Vdc Δt: 15.350 μs 1/Δt: 65.15 kHz 測量 搜索 t: 46.136 µs t: 61.486 µs Vout=388Vdc 结果表 绘图 10 More lout=4.9A fsw=65kHz u'- 434 0 L=300uH

Rise Time µ': 25.67 r Fall Time

Rise Time u': 70.49

/ 5.12 V

20 µs/div 200 µs SR: 1.25 GS/s 800 ps/pt

#### Results

Vgsmax: 6.32V Vdsmax: 434V ILmax: 12.52A



1 数学 参考 总线

Tr\_gs: 70.49ns Tf sw:10.58ns

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#### 6.2.2.Efficiency results



#### 6.2.3.Thermal performance

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#### Test conditions Vin=200Vdc Vout=388Vdc Iout=4.9A fsw=65kHz

Air speed:1200LFM

### Result

High side GaN: 41.9℃ Low side GaN: 60.3℃

## Appendix

### Appendix A: INNEHB650A5 PCB layout



Figure 8 The top layer of INNEHB650A5



Figure 9 The first middle layer of INNEHB650A5



Figure 10 The second middle layer of INNEHB650A5

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Figure 11 The bottom layer of INNEHB650A5



Figure 12 The top silkscreen of INNEHB650A5





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### Appendix B: INNEHB650A5 BOM

#### Table 3 BOM of INNEHB650A5

Designator	Comment	Description	Footprint	Quantity	
C1, C2, C3, C7, C10,					
C12, C14, C15, C16,					
C17, C19, C22, C24,	1uF/25V	1uF±10% 25V,X7R,0603,	0603	20	
C26, C27, C28, C29,					
C30, C35, C36					
C4, C4A, C5, C5A	0.1uF/1KV	0.1uF/1KV ,cap	1812	4	
C6, C8, C18, C20	100pF/50V	100PF±10%	0602	4	
		25V,X7R,0603	0005	4	
C9, C11, C21, C23	4 745/25/	4.7uF±10%	0905	4	
	4.7077230	25V,X7R,0603	6005	4	
D1, D2, D4, D5, D6, D7,	P16W/C	Diodo	500-222	0	
D9, D10	010003	Diode	302-323	0	
D3, D8	6.2V	Zener Diode	SOD-323	2	
Q1, Q2	INN650TA030AH	INNO GaN	TOLL	2	
R1, R4, R10, R13	100R	resistance	0603	4	
R2, R11	10R	resistance	0603	2	
R3, R5, R6, R12, R14,	2 24	resistance	0603	6	
R15		resistance	0005	0	
R7, R16	2.2R	resistance	0603	2	
'R8, R17, R20, R22	10K	resistance	0603	4	
R21, R23	82K	resistance	0603	2	
R9, R19	1K	resistance	0603	2	
R18	TBD	resistance	TBD	1	
T1 T2	VPT85BD-01A	transformer	XFMR-SMD_L7.5-	2	
11,12			W6.7-P2.54-LS7.7-BL	<i>۲</i>	
U1, U5	INS1001	Gate Driver	QFN10 3x3 2		
U2, U6	NSI8220	Isolator	SO-08	2	
U4, U8	VPS8504B	transformer driver	SOT23-6L	2	

### **Revision history**

Date	Versions	Description	Author
2023/7/26	1.0	First edition	AE Team
2023/12/27	1.1	Update INNEHB650A2 to	
		INNEHB650A5	ALTEAN

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## Reminder:

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## A

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